

### FNK N-Channel Enhancement Mode Power MOSFET

# **Description**

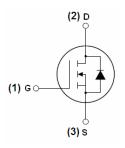
The FNK03N02E uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

- V<sub>DS</sub> =30V,I<sub>D</sub> =140A
  - $R_{DS(ON)}$  <3.0 m $\Omega$  @  $V_{GS}$ =10V
  - $R_{DS(ON)}$  <4.0m $\Omega$  @  $V_{GS}$  =4.5V
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

## **Application**

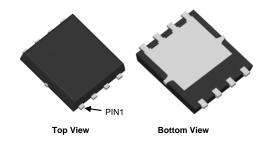
- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply



#### Schematic diagram



#### DFN5X6



### **Package Marking and Ordering Information**

	Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
Ī	FNK03N02E	FNK03N02E	DFN5x6-8L	-	-	-

#### Absolute Maximum Ratings (T<sub>c</sub>=25°Cunless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current-Continuous	I <sub>D</sub>	140	А
Drain Current-Continuous(T <sub>C</sub> =100°C)	I <sub>D</sub> (100℃)	105	Α
Pulsed Drain Current	I <sub>DM</sub>	560	Α
Maximum Power Dissipation	P <sub>D</sub>	130	W
Derating factor		0.87	W/°C
Single pulse avalanche energy (Note 5)	E <sub>AS</sub>	240	mJ
Operating Junction and Storage Temperature Range	$T_{J}$ , $T_{STG}$	-55 To 175	$^{\circ}$

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## **Thermal Characteristic**

Thermal Resistance, Junction-to-Case (Note 2)	$R_{ heta JC}$	1.15	°C/W
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Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics	<u>.                                      </u>					•	
Drain-Source Breakdown Voltage	ain-Source Breakdown Voltage BV <sub>DSS</sub> V <sub>GS</sub> =0V I <sub>D</sub> =250µA		30	34	-	V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V	-	-	1	μA	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA	
On Characteristics (Note 3)	<u>.                                      </u>					•	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	1.0	1.2	2.0	V	
Drain Course On State Decistance	-	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	-	2.1	3.4	m0	
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A		2.4	4.0	mΩ	
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =10V,I <sub>D</sub> =20A	32	-	-	S	
Dynamic Characteristics (Note4)	<u>.                                      </u>					•	
Input Capacitance	C <sub>lss</sub>		-	5400	-	PF	
Output Capacitance	Coss	$V_{DS}$ =15V, $V_{GS}$ =0V, F=1.0MHz	-	720	-	PF	
Reverse Transfer Capacitance	C <sub>rss</sub>	r=1.0lvlm2	-	560	-	PF	
Switching Characteristics (Note 4)							
Turn-on Delay Time	t <sub>d(on)</sub>		-	26	-	nS	
Turn-on Rise Time	t <sub>r</sub>	$V_{DD}$ =15 $V$ , $I_D$ =2 $A$ , $R_L$ =15 $\Omega$	-	24	-	nS	
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10 $V$ , $R_{G}$ =2.5 $\Omega$	-	91	-	nS	
Turn-Off Fall Time	t <sub>f</sub>		-	39	-	nS	
Total Gate Charge	Qg	\/ -45\/  -20A	-	38		nC	
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}=15V,I_{D}=30A,$ $V_{GS}=10V$	-	9		nC	
Gate-Drain Charge	Q <sub>gd</sub>	VGS-1UV	-	13		nC	
Drain-Source Diode Characteristics							
Diode Forward Voltage (Note 3)	$V_{SD}$	V <sub>GS</sub> =0V,I <sub>S</sub> =150A	-		1.2	V	
Diode Forward Current (Note 2)	Is		-	-	150	Α	
Reverse Recovery Time	t <sub>rr</sub>	TJ = 25°C, IF = 20A	-	42	-	nS	
Reverse Recovery Charge	Qrr	$di/dt = 100A/\mu s^{(Note3)}$	-	39	-	nC	

#### Notes:

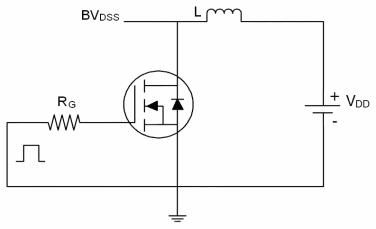
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2. Surface Mounted on FR4 Board, t ≤ 10 sec.
- **3.** Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2%.
- **4.** Guaranteed by design, not subject to production
- **5.** E<sub>AS</sub> condition : Tj=25  $^{\circ}$ C,V<sub>DD</sub>=20V,V<sub>G</sub>=10V,L=0.5mH,Rg=25 $\Omega$ , I<sub>AS</sub>=58.5A

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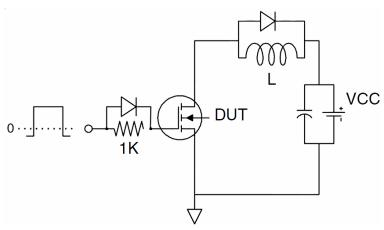


### **Test circuit**

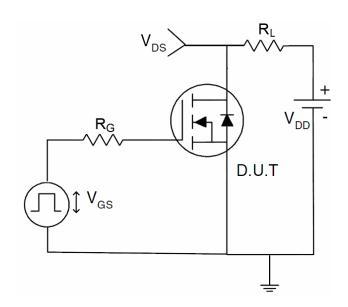
# 1) E<sub>AS</sub> Test Circuit



# 2) Gate Charge Test Circuit



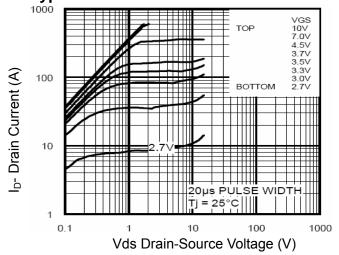
# 3) Switch Time Test Circuit



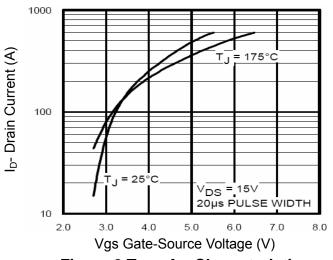
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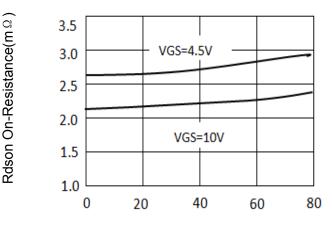
### Typical Electrical and Thermal Characteristics (Curves)



**Figure 1 Output Characteristics** 



**Figure 2 Transfer Characteristics** 



I<sub>D</sub>- Drain Current (A)

Figure 3 Rdson- Drain Current

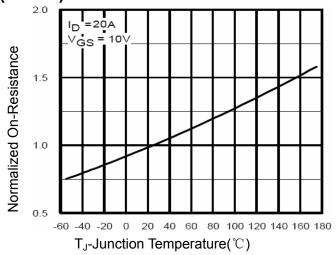


Figure 4 Rdson-JunctionTemperature

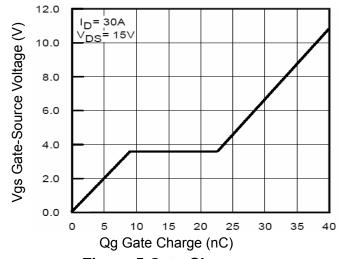


Figure 5 Gate Charge

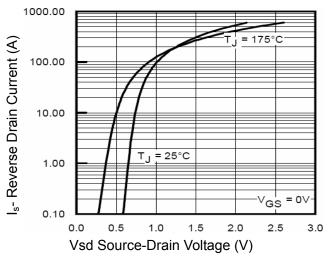


Figure 6 Source- Drain Diode Forward



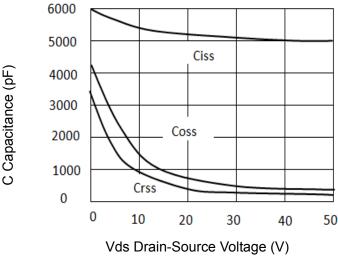
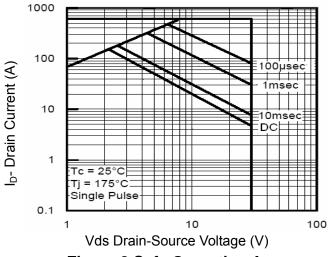


Figure 7 Capacitance vs Vds



**Figure 8 Safe Operation Area** 

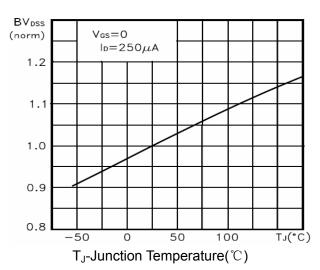


Figure 9 BV<sub>DSS</sub> vs Junction Temperature

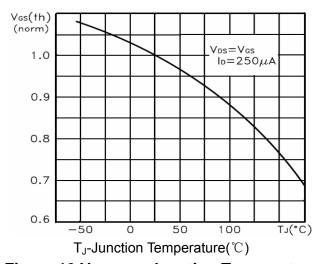


Figure 10 V<sub>GS(th)</sub> vs Junction Temperature

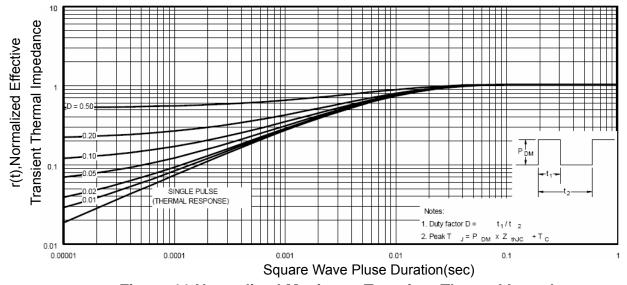
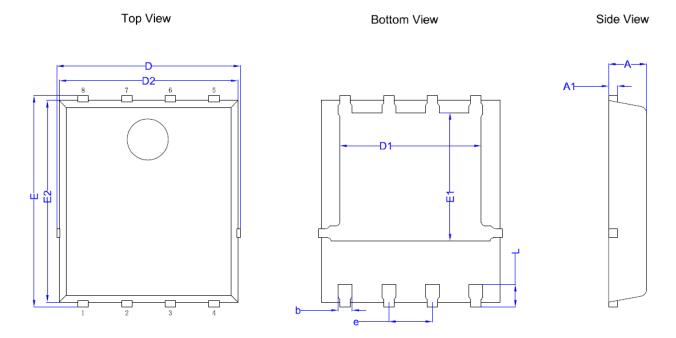


Figure 11 Normalized Maximum Transient Thermal Impedance

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# **DFN5X6-8L Package Information**



SYMBOL	MILLIMETER				
STIVIBOL	MIN	NOM	MAX		
Α	1.00	1.10	1.20		
A1	0.254 BSC				
D	5.15	5.35	5.55		
E	5.95	6.15	6.35		
D1	3.92	4.12	4.32		
E1	3.52	3.72	3.92		
D2	5.00	5.20	5.40		
E2	5.66	5.86	6.06		
е	1.27BSC				
b	0.31	0.41	0.51		
L	0.56	0.66	0.76		

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